Search Notes			

Application/Control No.	Applicant(s)/F Reexaminatio	Applicant(s)/Patent under Reexamination	
10/817,032	TANAKA, AT	TANAKA, ATSUSHI	
Examiner	Art Unit		

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DUSTIN NGUYEN

SEARCHED			
Class	Subclass	Date	Examiner
709	215, 220	2/14/2008	DN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
709	215, 220	2/14/2008	DN
711	114, 152	2/14/2008	DN
711	163, 202	2/14/2008	DN
710 726	36 1	2/14/2008	DN

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
update EAST search, IEEE, ACM, google, EPO, JPO, foreign search report	2/14/2008	DN
Inventor search	2/14/2008	DN
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